

Search Notes

Application/Control No.

10/782,859

Examiner

Y. J. Han

Applicant(s)/Patent under
Reexamination

YOKOYAMA ET AL.

Art Unit

2838

SEARCHED

Class	Subclass	Date	Examiner
323	241		
	246		
	268		
	274		
	275		
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	283		
	284		
	285		
	290	6/05	JH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
323	284		
	275		
	283	6/05	JH

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR